

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

### Product Summary

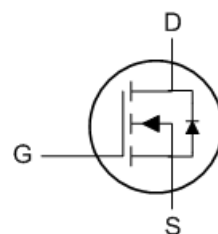
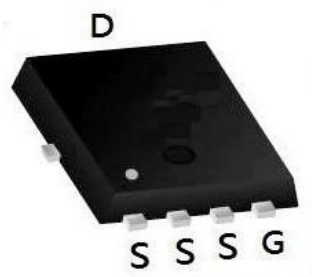


BVDSS	RDSON	ID
20V	2.2mΩ	100A

### Description

The XPX100N02RD is the high cell density trench N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The XPX100N02RD meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

### PDFN5060-8L Pin Configuration



### Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	20	V
$V_{GS}$	Gate-Source Voltage	$\pm 12$	V
$I_D@T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^{1,6}$	100	A
$I_D@T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^{1,6}$	63	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	400	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	306	mJ
$I_{AS}$	Avalanche Current	---	A
$P_D@T_C=25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	69	W
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$

### Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	---	---	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	---	1.8	$^\circ\text{C/W}$

**Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	20	---	---	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA	---	---	---	V/ °C
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> =17.5A	---	---	---	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =17.5A	---	2.2	2.9	
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =13A	---	2.7	3.5	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	0.5	---	1	V
ΔV <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient		---	---	---	mV/ °C
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	---	---	1	uA
		V <sub>DS</sub> =20V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C	---	---	100	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±12V, V <sub>DS</sub> =0V	---	---	±100	nA
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =17.5A	---	88	---	S
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =10V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =17.5A	---	70	---	nC
Q <sub>gs</sub>	Gate-Source Charge		---	10	---	
Q <sub>gd</sub>	Gate-Drain Charge		---	14	---	
T <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DS</sub> =10V, V <sub>GS</sub> =4.5V, R <sub>G</sub> =3Ω, R <sub>L</sub> =0.5Ω	---	8	---	ns
T <sub>r</sub>	Rise Time		---	20	---	
T <sub>d(off)</sub>	Turn-Off Delay Time		---	75	---	
T <sub>f</sub>	Fall Time		---	82	---	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V, f=1MHz	---	5670	---	pF
C <sub>oss</sub>	Output Capacitance		---	460	---	
C <sub>rss</sub>	Reverse Transfer Capacitance		---	416	---	

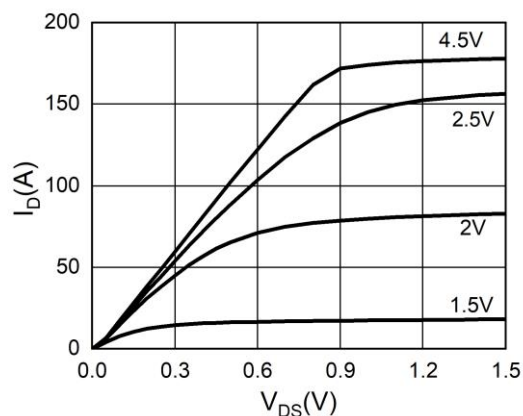
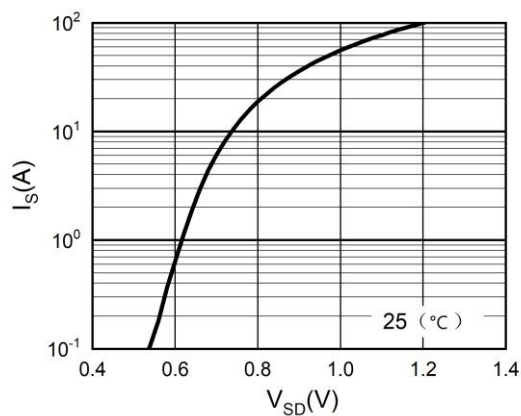
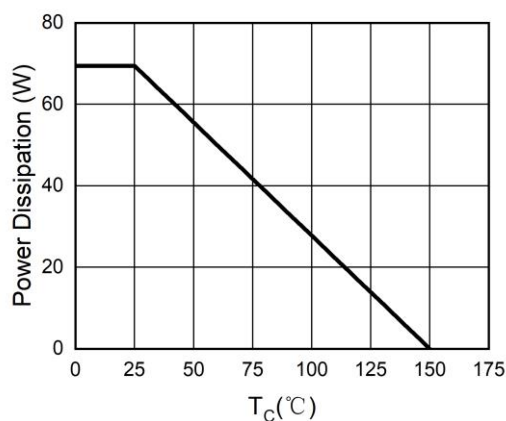
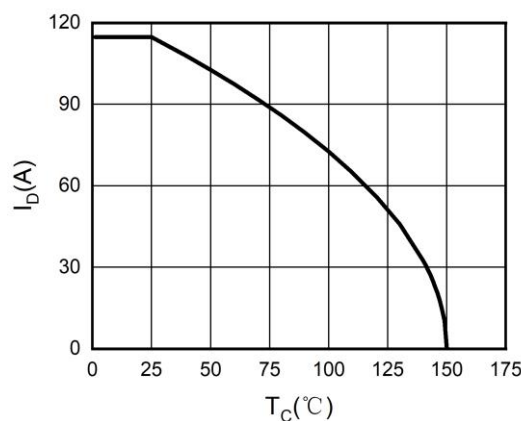
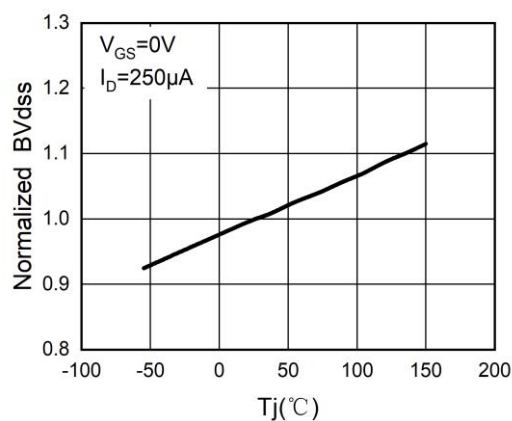
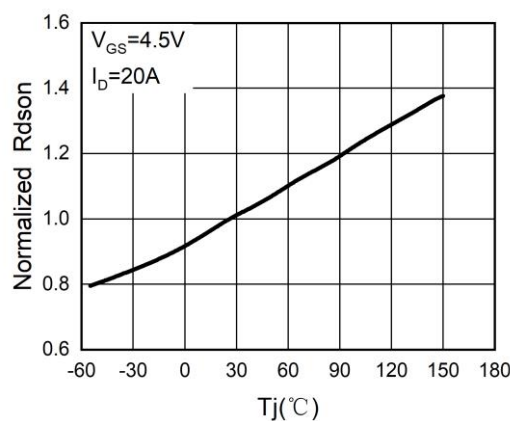
**Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I <sub>S</sub>	Continuous Source Current <sup>1,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current	---	---	100	A
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =21A, T <sub>J</sub> =25°C	---	---	1	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> =17.5A, di/dt=100A/μs,	---	15	---	nS
Q <sub>rr</sub>	Reverse Recovery Charge	T <sub>J</sub> =25°C	---	6	---	nC

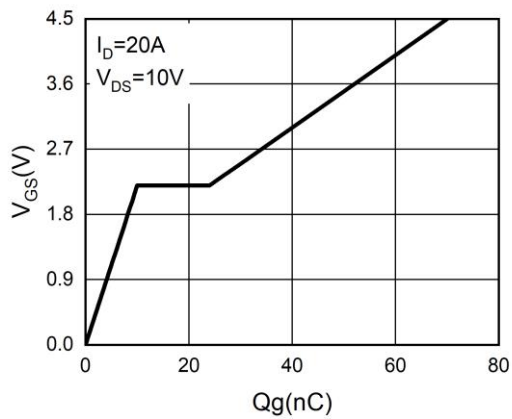
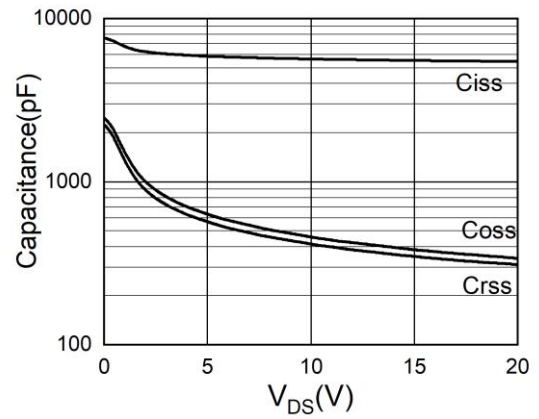
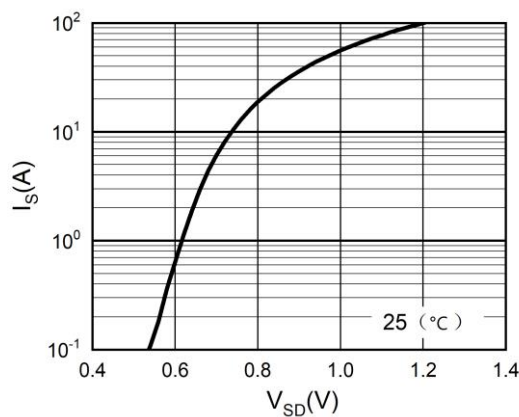
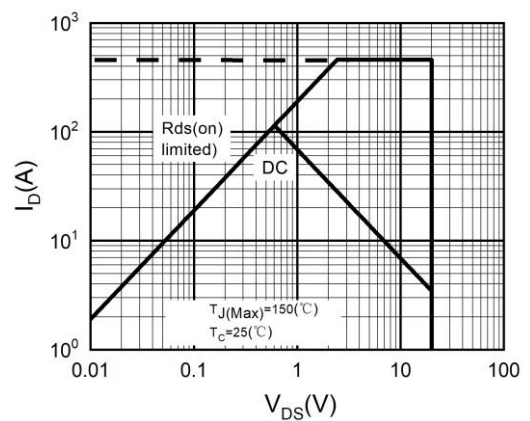
Note :

- 1..Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2.EAS condition: T<sub>J</sub>=25°C, V<sub>DD</sub>=10V, V<sub>G</sub>=10V, R<sub>G</sub>=25Ω, L=0.5mH.
- 3.Repetitive Rating: Pulse width limited by maximum junction temperature.e.

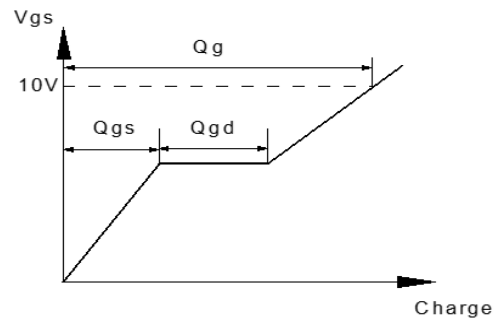
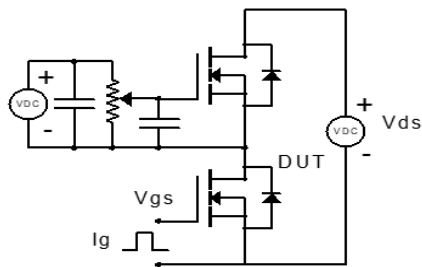
## Typical Electrical And Thermal Characteristics (Curves)

**Figure 1. Output Characteristics**

**Figure 2. Transfer Characteristics**

**Figure 3. Power Dissipation**

**Figure 4. Drain Current**

**Figure 5.  $BV_{DSS}$  vs Junction Temperature**

**Figure 6.  $R_{DS(ON)}$  vs Junction Temperature**


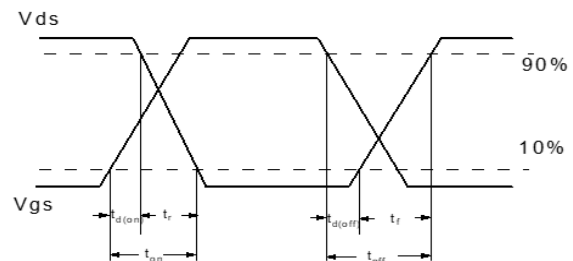
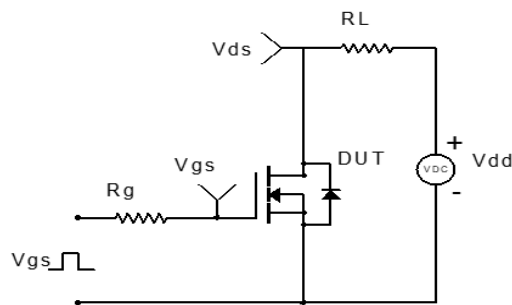
## Typical Electrical And Thermal Characteristics (Curves)

**Figure 7. Gate Charge Waveforms**

**Figure 8. Capacitance**

**Figure 9. Body-Diode Characteristics**

**Figure 10. Maximum Safe Operating Area**


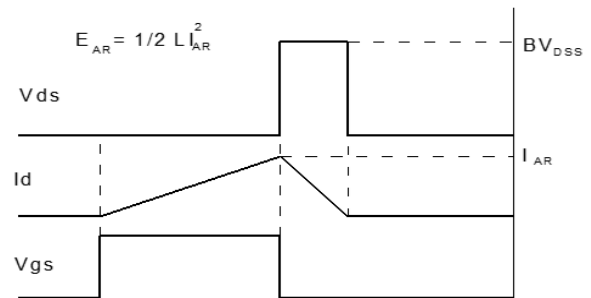
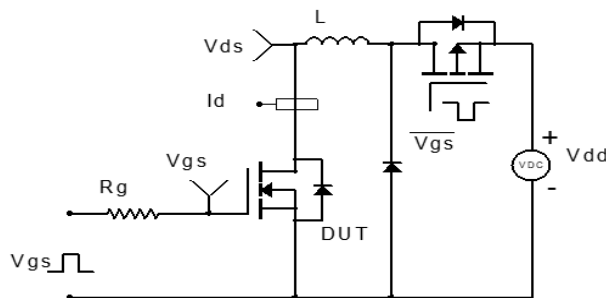
## Test Circuit



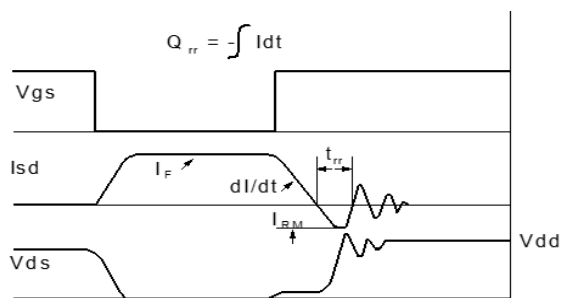
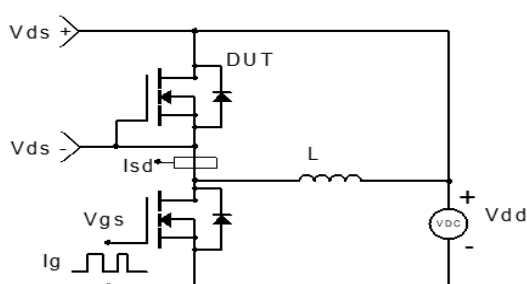
**Figure 1: Gate Charge Test Circuit & Waveform**



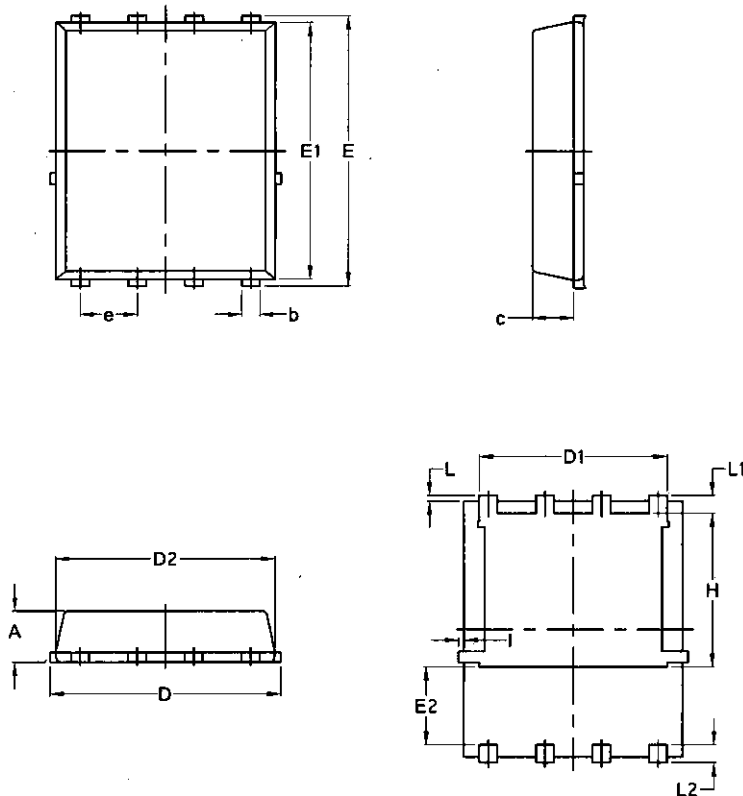
**Figure 2: Resistive Switching Test Circuit & Waveform**



**Figure 3: Unclamped Inductive Switching Test Circuit & Waveform**



**Figure 4: Diode Recovery Test Circuit & Waveform**

**Package Mechanical Data-PDFN5060-8L-Single**


Symbol	Common			
	mm		Inch	
	Mim	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C $\pm$ 5°C	5sec $\pm$ 1 sec
Pb-Free device	260°C $\pm$ 0/-5°C	5sec $\pm$ 1 sec



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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